

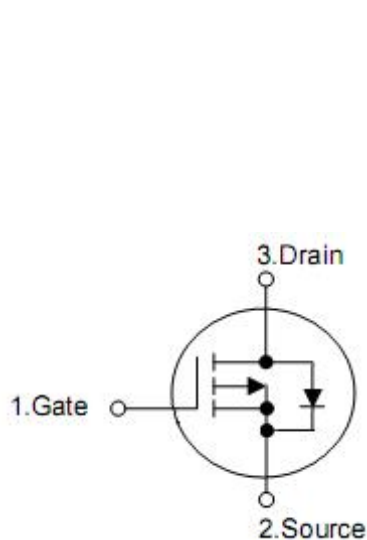
## 1. Description

The KIA3415 uses advanced trench technology to provide excellent  $R_{DS(on)}$ , low gate charge and operation with gate voltages as low as 1.8V. This device is suitable for use as a load switch or in PWM applications. Standard Product KIA3415 is Pb-free (meets ROHS & Sony 259 specifications). KIA3415 is a Green Product ordering option. KIA3415 is electrically identical.

## 2. Features

- n  $V_{DS}(V) = -20V$
- n  $I_D = -4.0A$
- n  $R_{DS(on)} < 45m\Omega (V_{GS} = -4.5V, I_D = -4.0A)$
- n  $R_{DS(on)} < 54m\Omega (V_{GS} = -2.5V, I_D = -4.0A)$
- n  $R_{DS(on)} < 75m\Omega (V_{GS} = -1.8V, I_D = -2.0A)$

## 3. Symbol



Pin	Function
1	Gate
2	Source
3	Drain

#### 4. Absolute maximum ratings

(T<sub>A</sub>=25°C, unless otherwise noted)

Parameter	Symbol	Rating	Units
Drain-source voltage	V <sub>DS</sub>	-20	V
Gate-source voltage	V <sub>GS</sub>	±8	V
Continuous drain current <sup>A</sup>	I <sub>D</sub>	T <sub>A</sub> =25°C	-4.0
		T <sub>A</sub> =70°C	-3.5
Pulsed drain current <sup>B</sup>	I <sub>DM</sub>	-30	A
Total power dissipation <sup>A</sup>	P <sub>D</sub>	T <sub>A</sub> =25 °C	1.4
		T <sub>A</sub> =70°C	0.9
Junction and storage temperature range	T <sub>J</sub> , T <sub>STG</sub>	-55 to 150	°C

#### 5. Thermal characteristics

Parameter	Symbol	Typ	Max	Unit
Maximum junction-ambient <sup>A</sup> (t≤10s)	R <sub>θJA</sub>	65	90	°C/W
Maximum junction-ambient <sup>A</sup>	R <sub>θJA</sub>	85	125	°C/W
Maximum junction-Lead <sup>C</sup>	R <sub>θJL</sub>	43	60	°C/W

## 6. Electrical characteristics

(T<sub>A</sub>=25°C, unless otherwise noted)

Parameter	Symbol	Test Conditions	Min	Typ	Max	Units
Drain-source breakdown voltage	BV <sub>DSS</sub>	V <sub>GS</sub> =0V, I <sub>D</sub> =-250μA	-20	-	-	V
Zero gate voltage drain current	I <sub>DSS</sub>	V <sub>DS</sub> =-16V, V <sub>GS</sub> =0V	-	-	-50	nA
Gate- body leakage current	I <sub>GSS</sub>	V <sub>GS</sub> =±8V, V <sub>DS</sub> =0V	-	-	±100	nA
Gate threshold voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =-250μA	-0.4	-0.55	-0.8	V
On state drain current	I <sub>D(on)</sub>	V <sub>GS</sub> =-4.5V, V <sub>DS</sub> =-5V	-25	-	-	A
Static drain-source on-resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> =-4.5V, I <sub>D</sub> =-4.0A	-	40	45	mΩ
		V <sub>GS</sub> =-2.5V, I <sub>D</sub> =-4.0A	-	50	54	
		V <sub>GS</sub> =-1.8V, I <sub>D</sub> =-2.0A	-	70	75	
Forward transconductance	g <sub>fs</sub>	V <sub>DS</sub> =-5.0V, I <sub>D</sub> =-4A	8	16	-	S
Diode forward voltage	V <sub>SD</sub>	V <sub>GS</sub> =0V, I <sub>S</sub> =-1A	-	-0.78	-1.28	V
Maximum body-diode continuous current	I <sub>S</sub>		-	-	-2.2	A
Input capacitance	C <sub>iss</sub>	V <sub>DS</sub> =-10V, V <sub>GS</sub> =0V, f=1MHz	-	1450	-	pF
Output capacitance	C <sub>oss</sub>		-	205	-	
Reverse transfer capacitance	C <sub>rss</sub>		-	160	-	
Gate resistance	R <sub>g</sub>	V <sub>DS</sub> =0V, V <sub>GS</sub> =0V, f=1MHz	-	6.5	-	Ω
Total gate charge	Q <sub>g</sub>	V <sub>DS</sub> =-10V, V <sub>GS</sub> =-4.5V I <sub>D</sub> =-4.0A	-	17.2	-	nC
Gate-source charge	Q <sub>gs</sub>		-	1.3	-	
Gate-drain charge	Q <sub>gd</sub>		-	4.5	-	
Turn-on delay time	t <sub>d(on)</sub>	V <sub>DS</sub> =-10V, R <sub>L</sub> =2.5Ω,, R <sub>G</sub> =3Ω, V <sub>GS</sub> =-4.5V	-	9.5	-	ns
Rise time	t <sub>r</sub>		-	17	-	
Turn-off delay time	t <sub>d(off)</sub>		-	94	-	
Fall time	t <sub>f</sub>		-	35	-	
Reverse recovery time	t <sub>rr</sub>	IF=-4A, dl/dt=100A/μs,	-	31	-	nS
Reverse recovery charge	Q <sub>rr</sub>		-	13.8	-	nC

Note: A. The value of R<sub>θJA</sub> is measured with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with T<sub>A</sub>=25°C. The value in any given application depends on the user's specific board design. The current rating is based on the t<sub>≤10s</sub> thermal resistance rating.

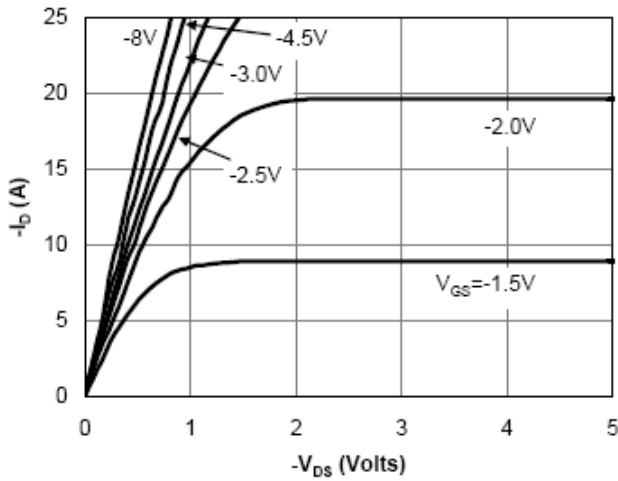
B. Repetitive rating, pulse width limited by junction temperature.

C. The R<sub>θJA</sub> the sum of the thermal impedance from junction to lead R<sub>θJA</sub> and lead to ambient.

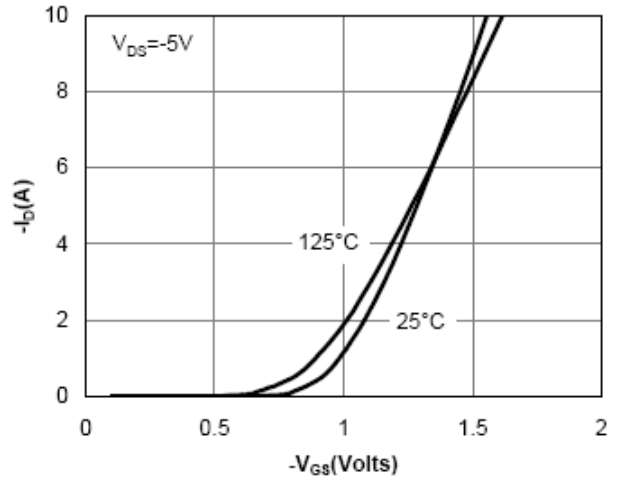
D. The static characteristics in Figures 1 to 6, 12, 14 are obtained using 80μs pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with T<sub>A</sub>=25°C. The SOA curve provides a single pulse rating.

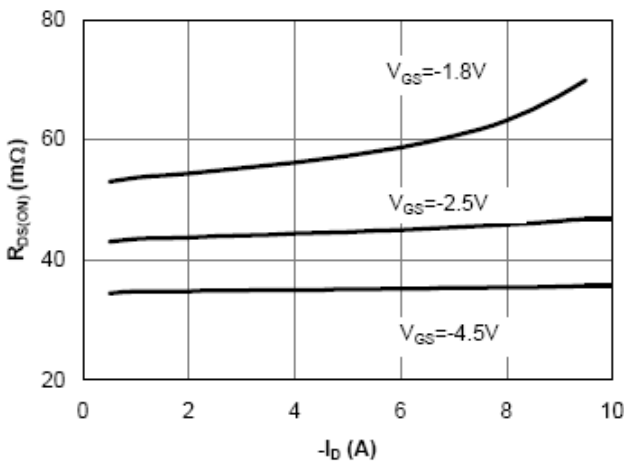
**7. Test circuits and waveforms**



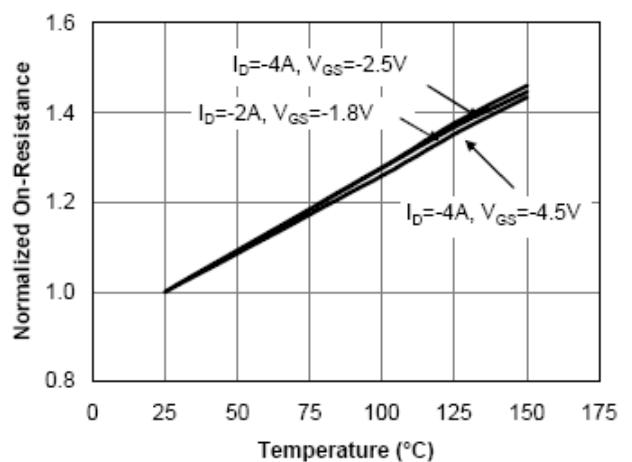
**Fig 1: On-Region Characteristics**



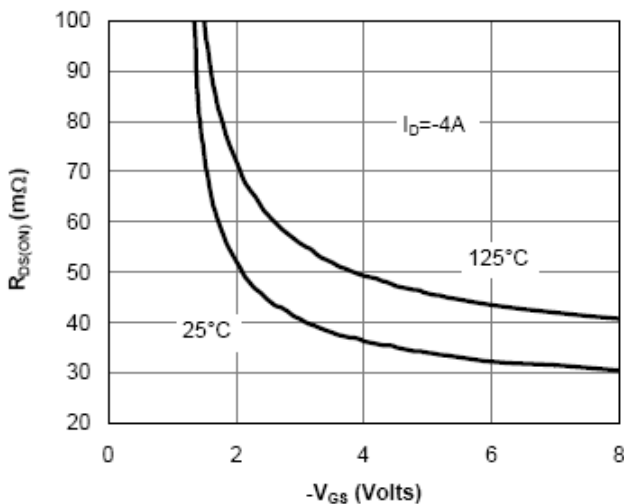
**Figure 2: Transfer Characteristics**



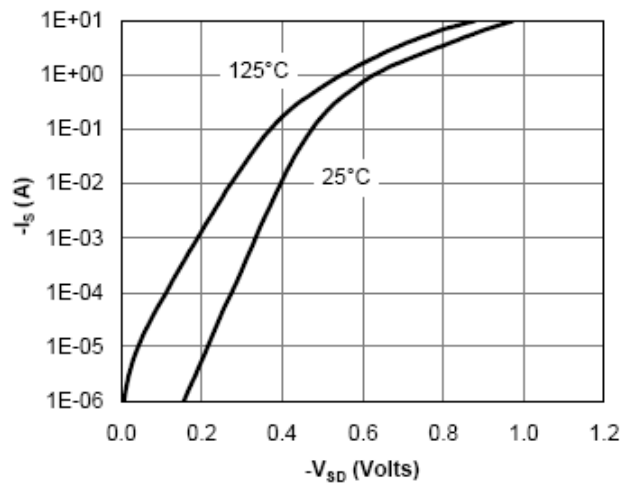
**Figure 3: On-Resistance vs. Drain Current and Gate Voltage**



**Figure 4: On-Resistance vs. Junction Temperature**



**Figure 5: On-Resistance vs. Gate-Source Voltage**



**Figure 6: Body-Diode Characteristics**

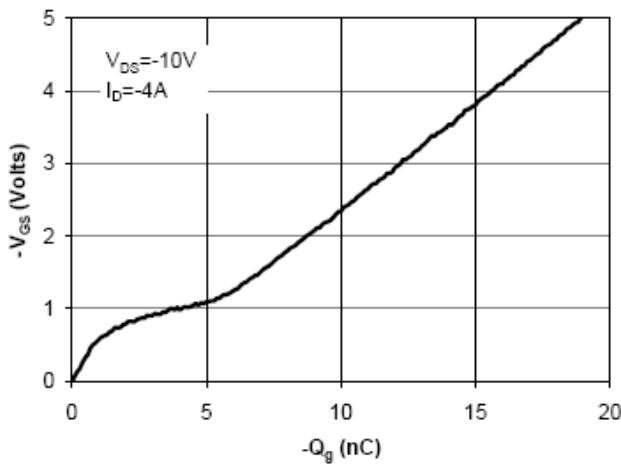


Figure 7: Gate-Charge Characteristics

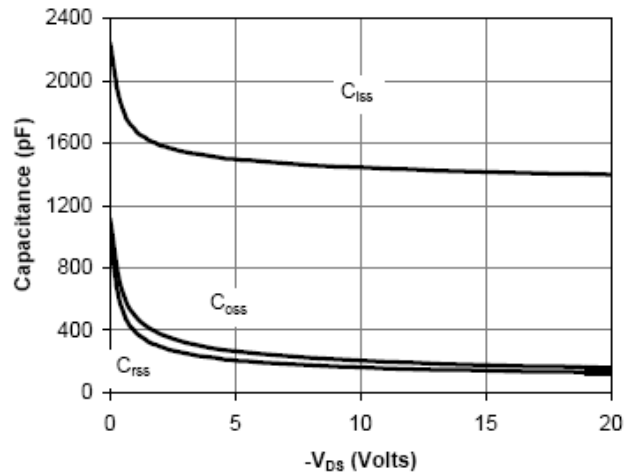


Figure 8: Capacitance Characteristics

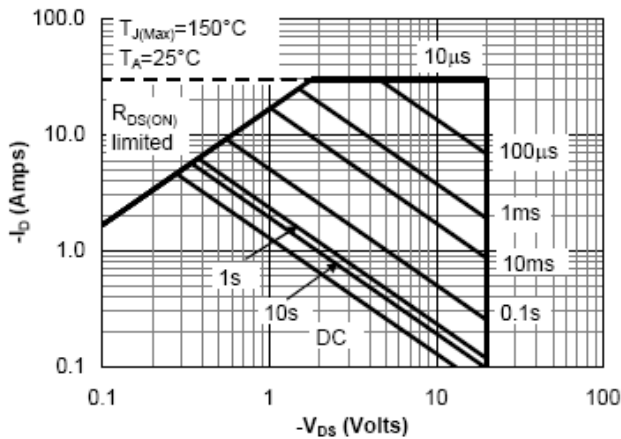


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

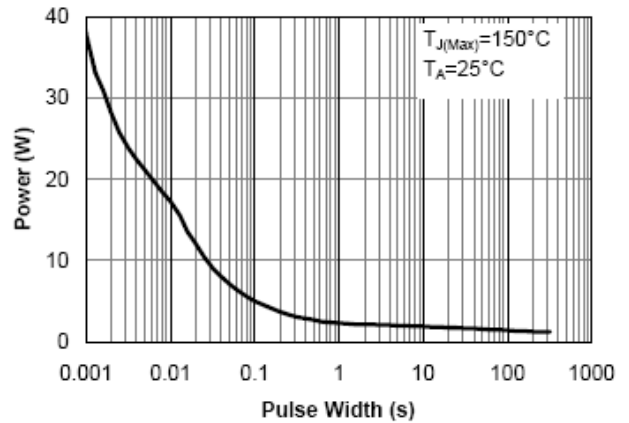


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

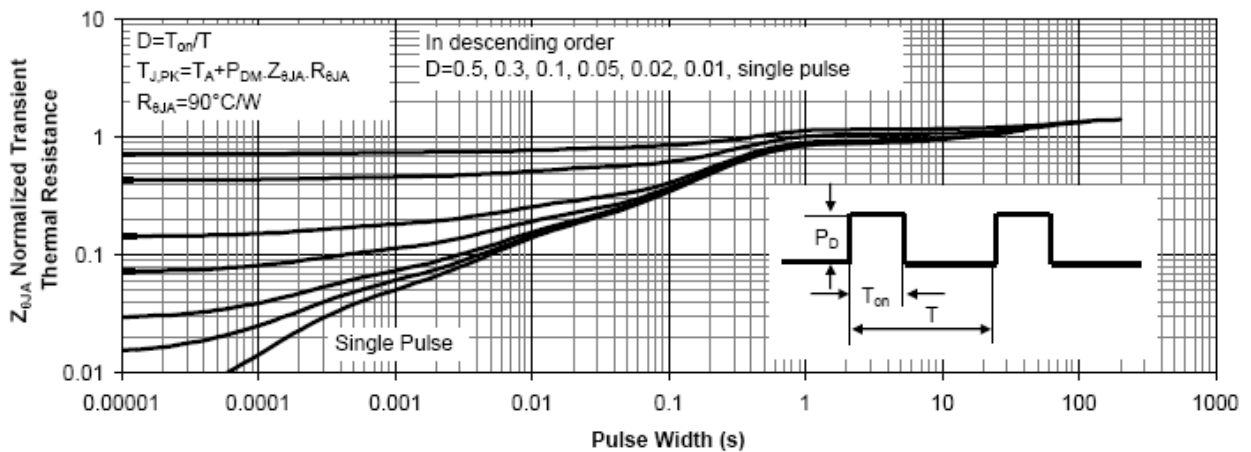


Figure 11: Normalized Maximum Transient Thermal Impedance